US00D745687S

(12) **United States Design Patent**
Kitayama

(10) **Patent No.: US D745,687 S**
(45) **Date of Patent: ** Dec. 15, 2015**

(54) **PROBE FOR AN ULTRASONIC DIAGNOSIS APPARATUS**

(71) Applicants: **Kabushiki Kaisha Toshiba**, Minato-ku, Tokyo (JP); **Toshiba Medical Systems Corporation**, Otawara-shi, Tochigi-ken (JP)

(72) Inventor: **Masahiko Kitayama**, Tokyo (JP)

(73) Assignees: **Kabushiki Kaisha Toshiba**, Minato-ku, Tokyo (JP); **Toshiba Medical Systems Corporation**, Otawara-shi, Tochigi-ken (JP)

(**) Term: **14 Years**

(21) Appl. No.: **29/513,357**

(22) Filed: **Dec. 30, 2014**

(30) **Foreign Application Priority Data**

Jun. 30, 2014 (JP) 2014-014217

(51) **LOC (10) Cl.** **24-01**

(52) **U.S. Cl.**
USPC **D24/187**

(58) **Field of Classification Search**
USPC D24/133, 137, 158, 186, 187; D10/78; 600/407, 446, 439, 461; 378/98.7, 378/98.8, 189
CPC A61B 8/445; A61B 8/4455; A61B 8/4461
See application file for complete search history.

(56) **References Cited**

U.S. PATENT DOCUMENTS

4,756,313 A * 7/1988 Terwilliger A61B 8/12 600/104
4,930,515 A * 6/1990 Terwilliger A61B 8/12 600/446

(Continued)

FOREIGN PATENT DOCUMENTS

JP	960414	8/1996
JP	1128456	12/2001

Primary Examiner — Anhdao Doan
(74) *Attorney, Agent, or Firm* — Banner & Witcoff, Ltd.

(57) **CLAIM**

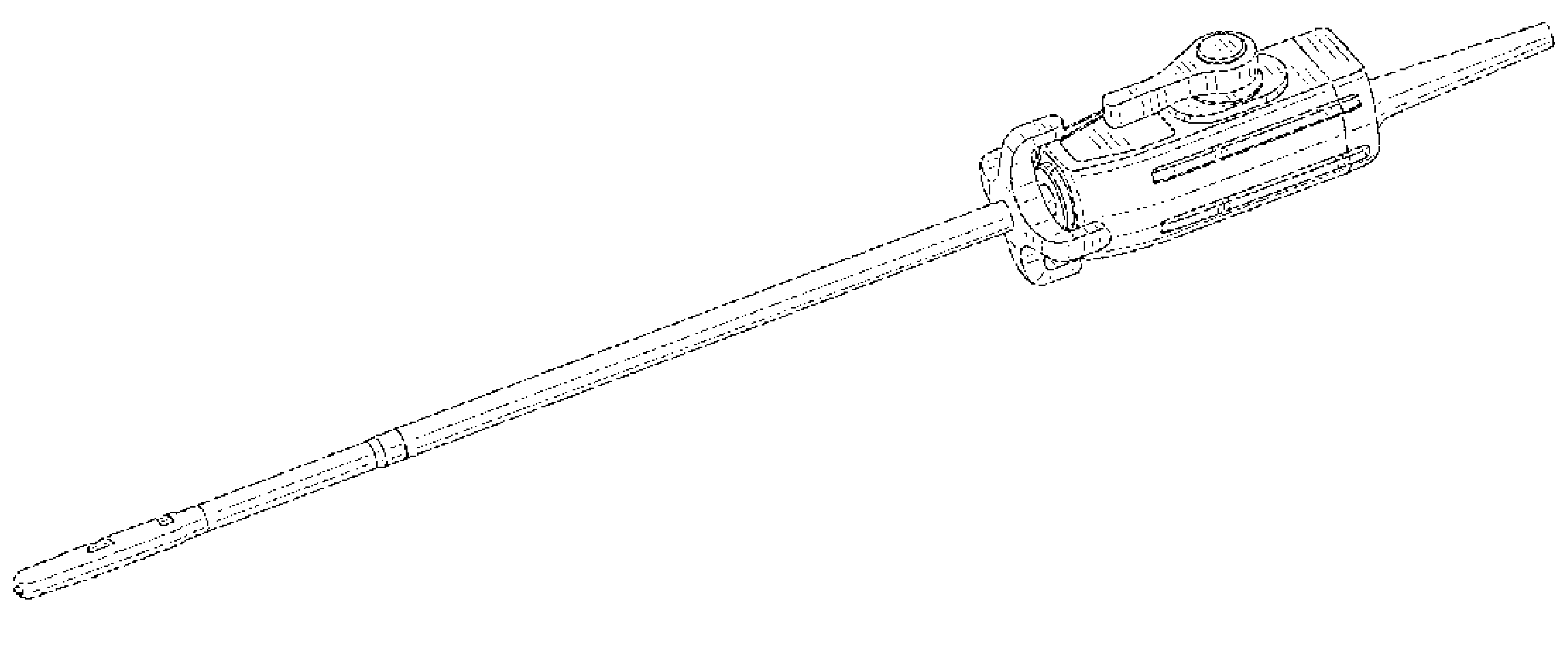
The ornamental design for a probe for an ultrasonic diagnosis apparatus, as shown and described.

DESCRIPTION

FIG. **1** is a front, top and left side perspective view of a probe for an ultrasonic diagnosis apparatus, showing my new design;
FIG. **2** is a rear, top and right side perspective view thereof;
FIG. **3** is a front view thereof;
FIG. **4** is a left side view thereof;
FIG. **5** is a right side view thereof;
FIG. **6** is a top view thereof;
FIG. **7** is a bottom view thereof;
FIG. **8** is a rear view thereof;
FIG. **9** is a cross sectional view thereof, taken along the line **9-9** in FIG. **4** with its internal mechanisms omitted;
FIG. **10** is an enlarged fragmented view thereof, taken along the line **10** of FIG. **3**;
FIG. **11** is an enlarged fragmented view thereof, taken along the line **11** of FIG. **3**;
FIG. **12** is an enlarged left side view thereof;
FIG. **13** is an enlarged fragmented view thereof, taken along the line **13** of FIG. **6**;
FIG. **14** is an enlarged fragmented view thereof, taken along the line **14** of FIG. **6**;
FIG. **15** is an enlarged fragmented view thereof, taken along the line **15** of FIG. **9**;
FIG. **16** is an enlarged fragmented view thereof, taken along the line **16** of FIG. **9**; and,
FIG. **17** is a perspective view thereof in an alternate condition of use.

The broken lines in FIGS. **3**, **6**, **9**, **10**, **11**, **13**, **14**, **15** and **16** are included to indicate the point at which the magnified view is cut off. The broken lines showing the inner portions in FIGS. **9**, **15**, **16** are included for the purpose of illustrating unclaimed portions of the probe. None of the broken lines form part of the claimed design.

1 Claim, 9 Drawing Sheets



(56) References Cited

U.S. PATENT DOCUMENTS

D320,078	S	*	9/1991	Terwilliger	D24/138
5,938,616	A	*	8/1999	Eaton	A61B 1/0052 600/446
D553,249	S	*	10/2007	Wakisaka	D24/186
D703,331	S	*	4/2014	Kitayama	D24/187
2002/0138080	A1	*	9/2002	Chon	A61F 9/00745 606/103

* cited by examiner

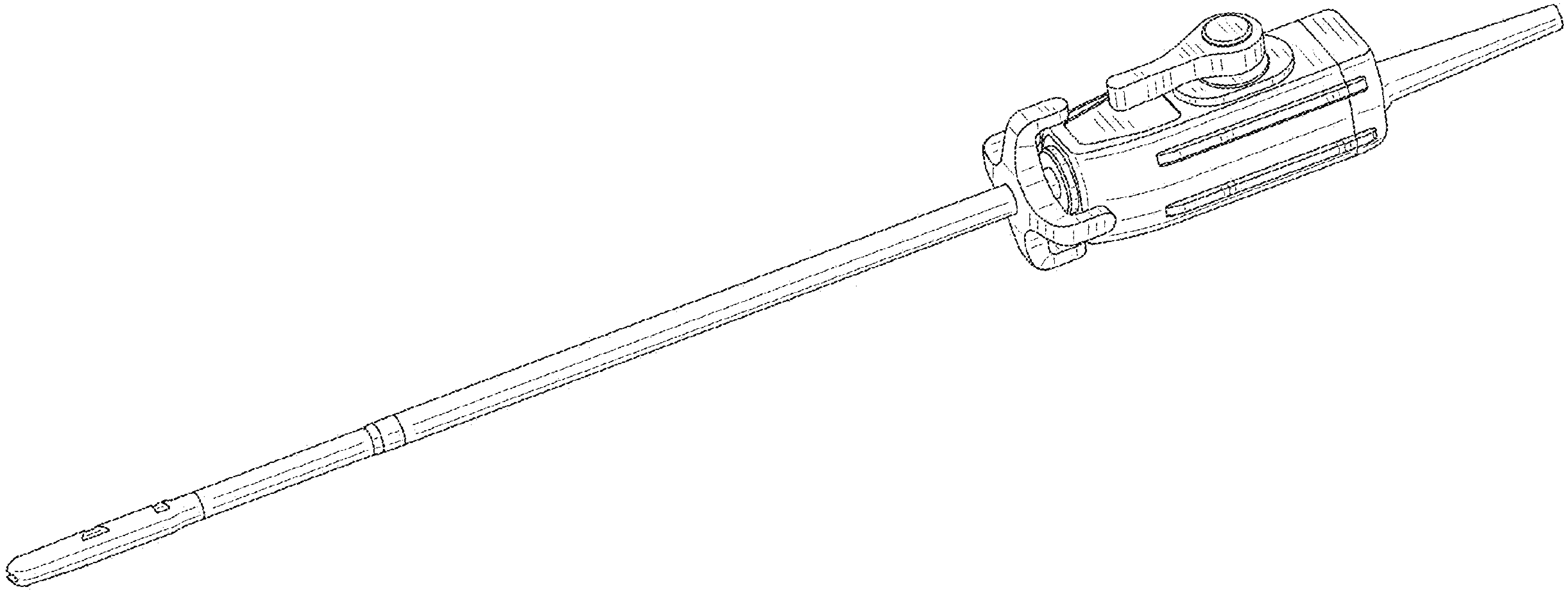


Fig. 1

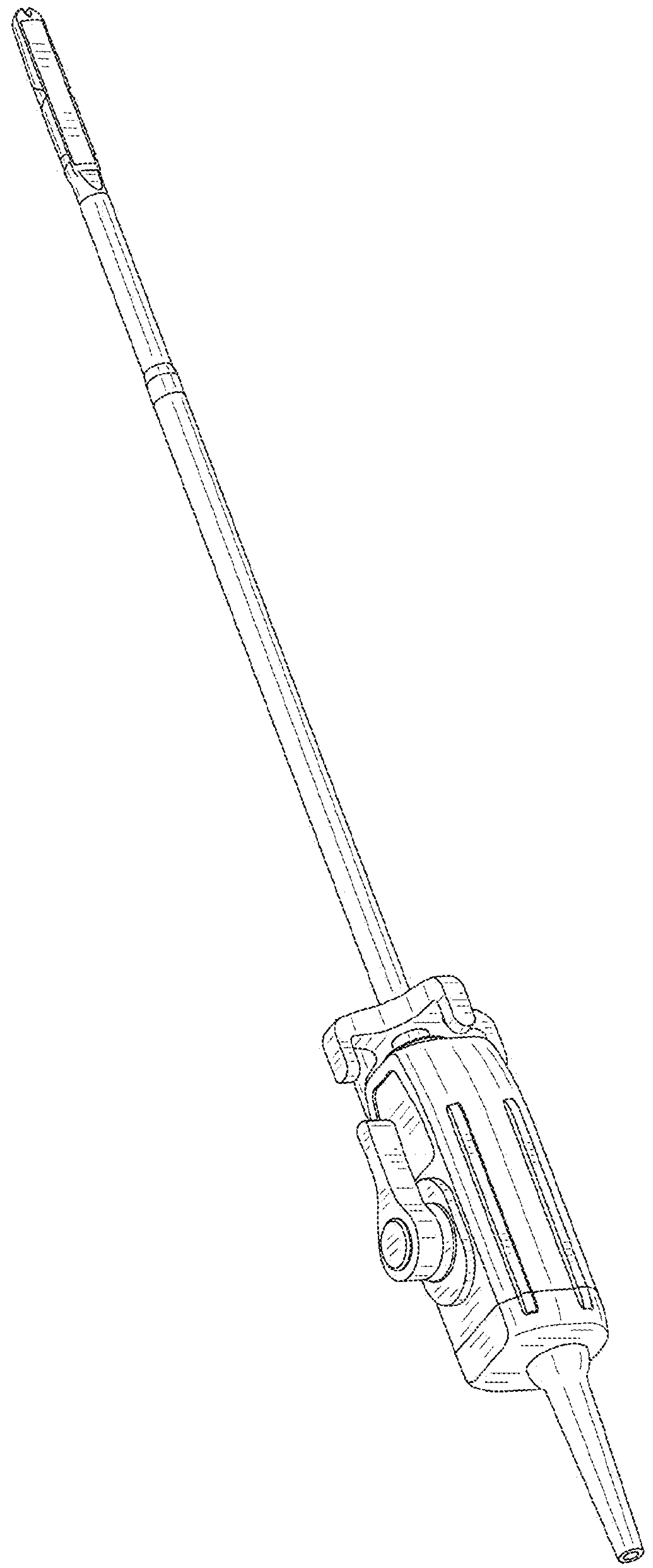


Fig. 2

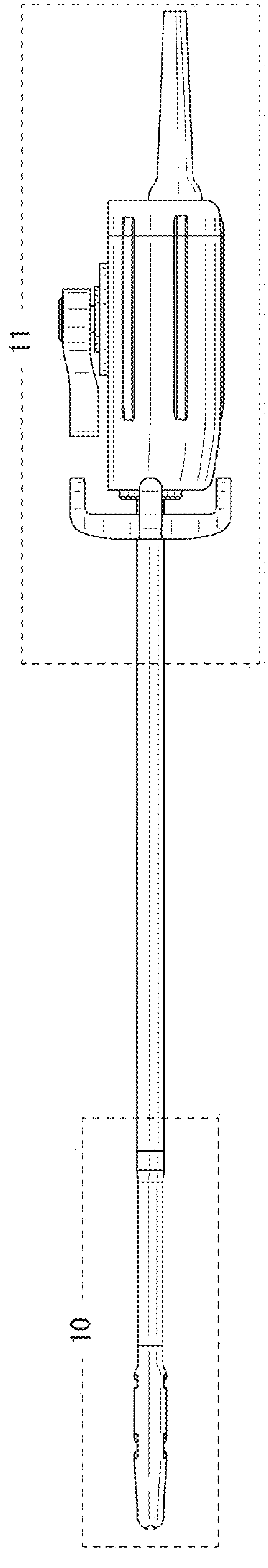


Fig.3

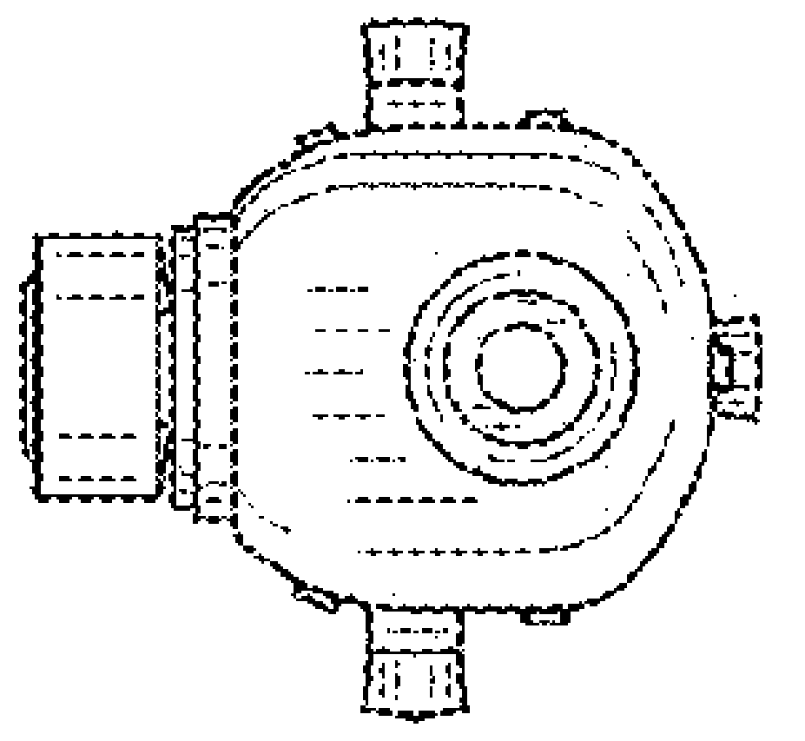


Fig.5

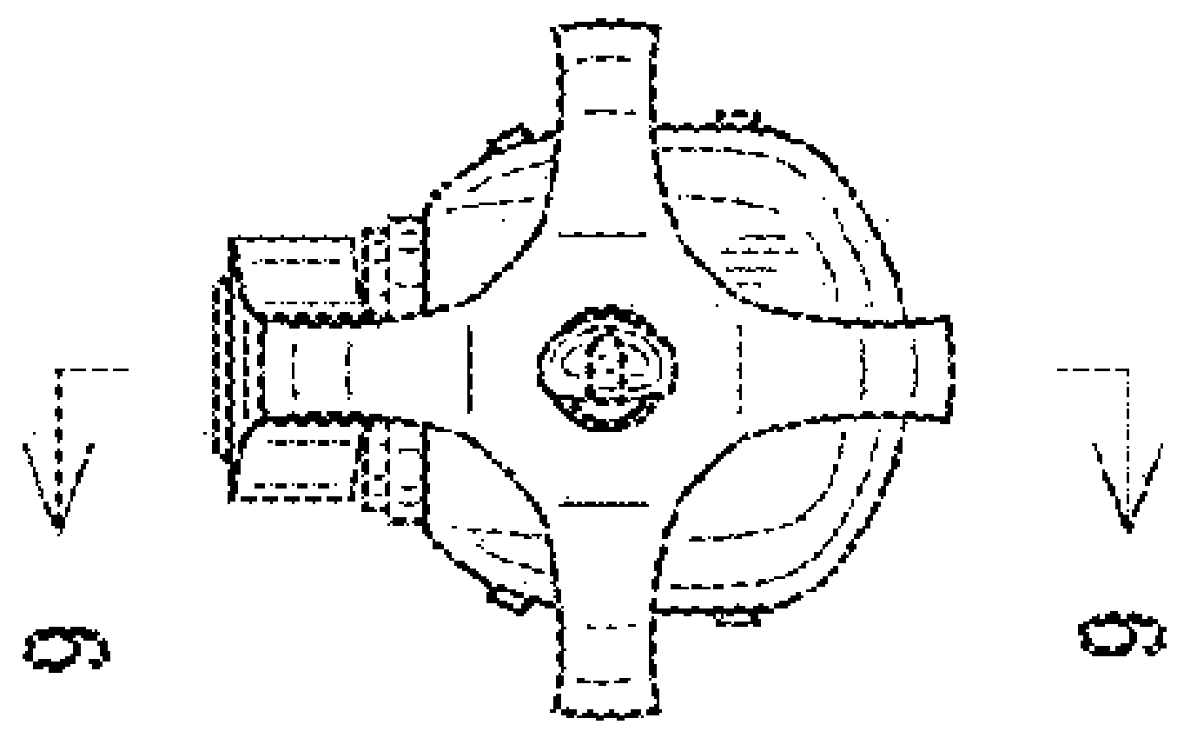


Fig.4

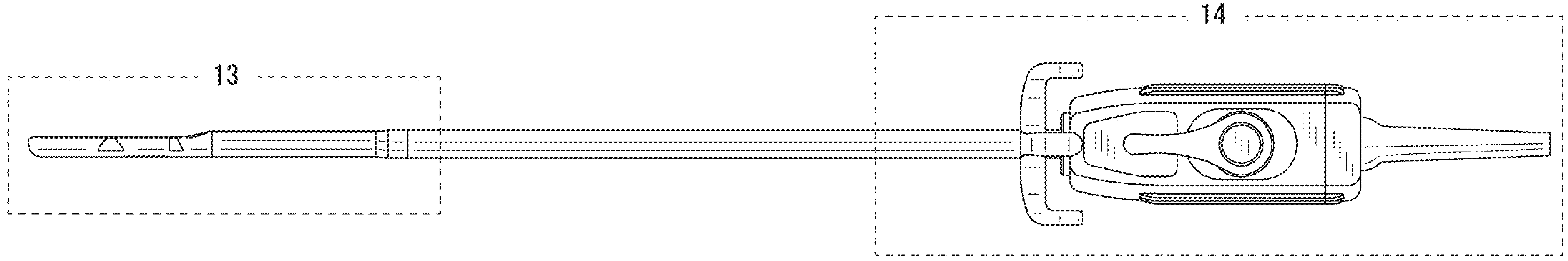


Fig.6

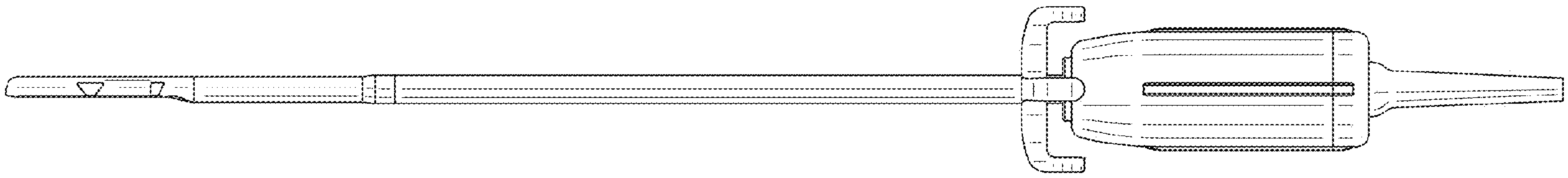


Fig.7

Fig.8

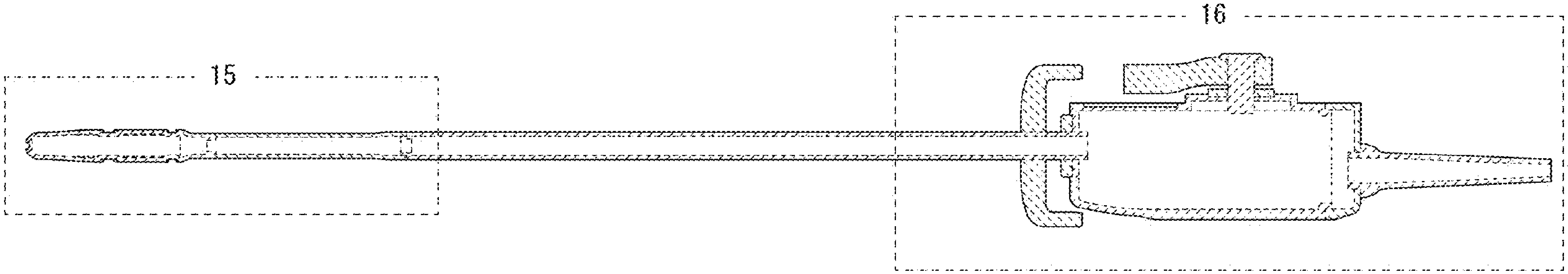


Fig.9

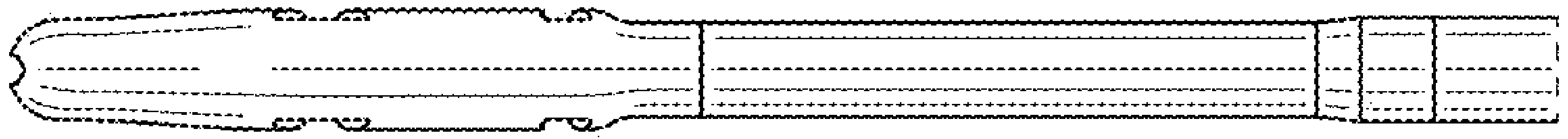


Fig.10

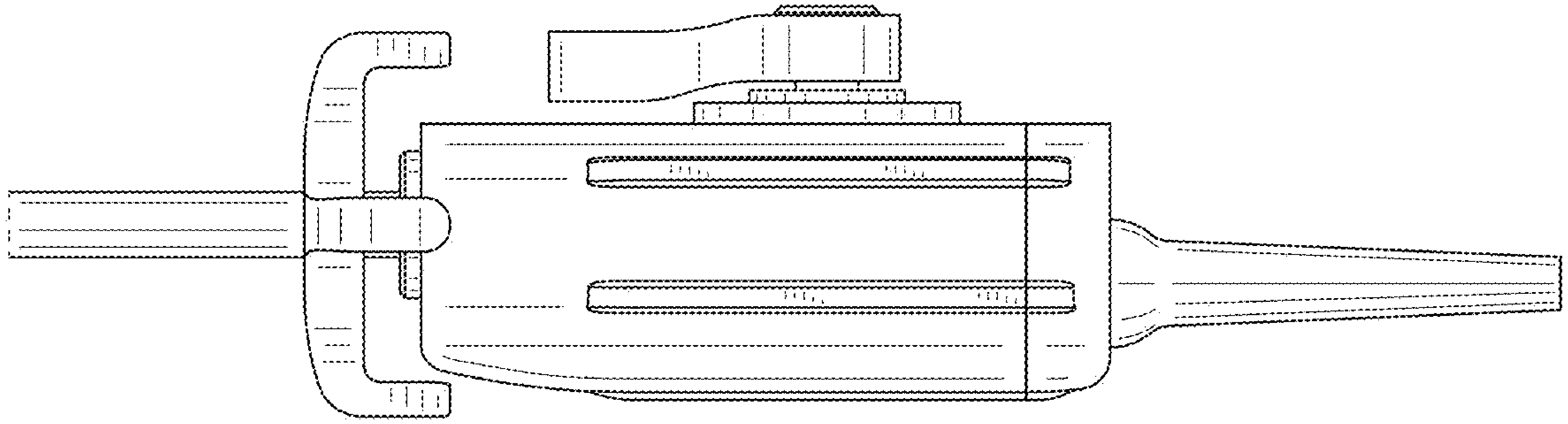


Fig.11

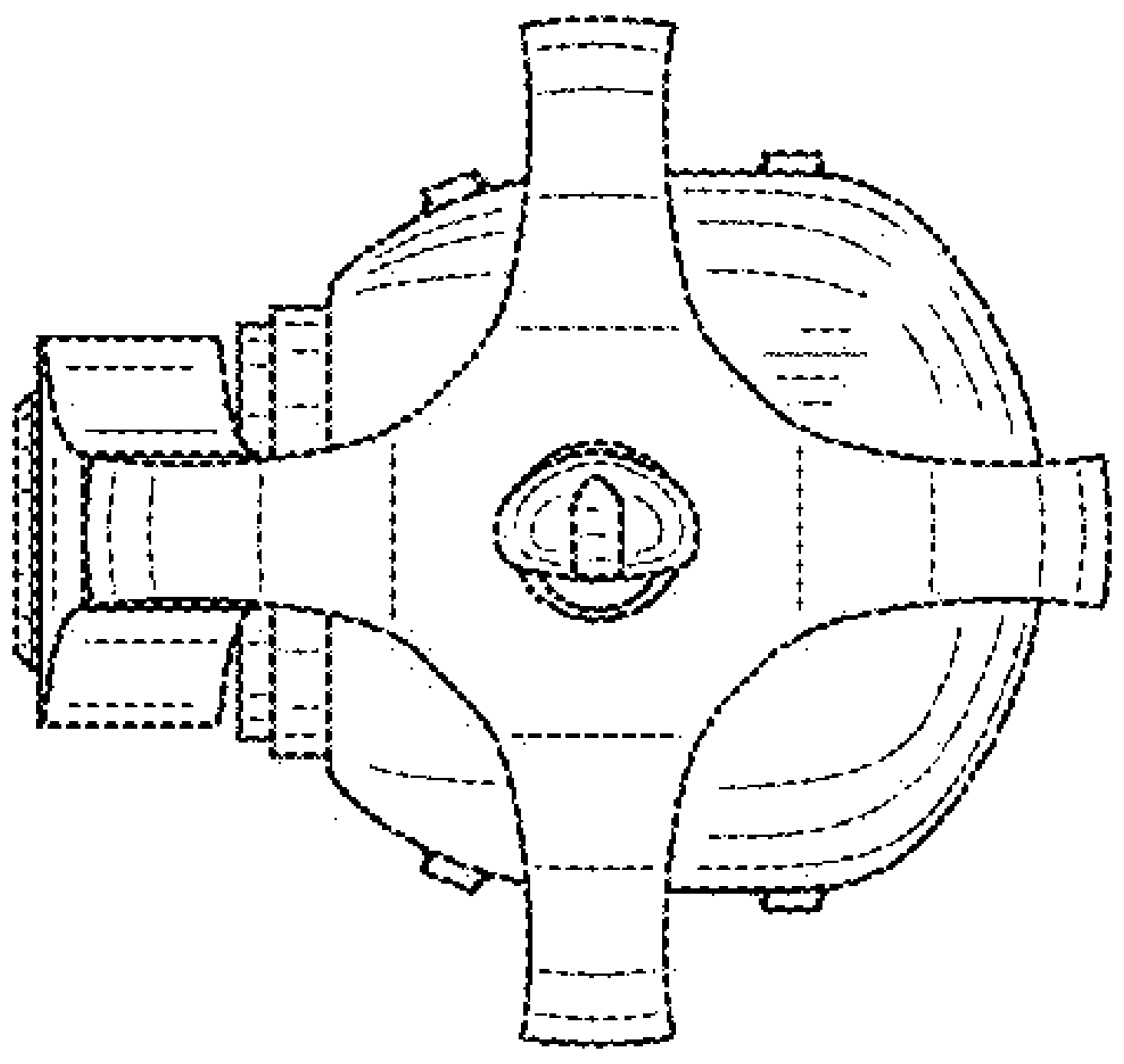


Fig. 12

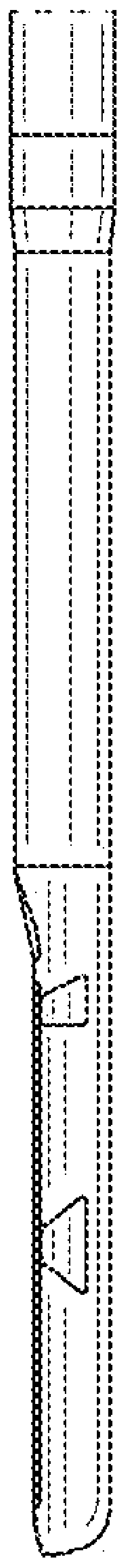


Fig. 13

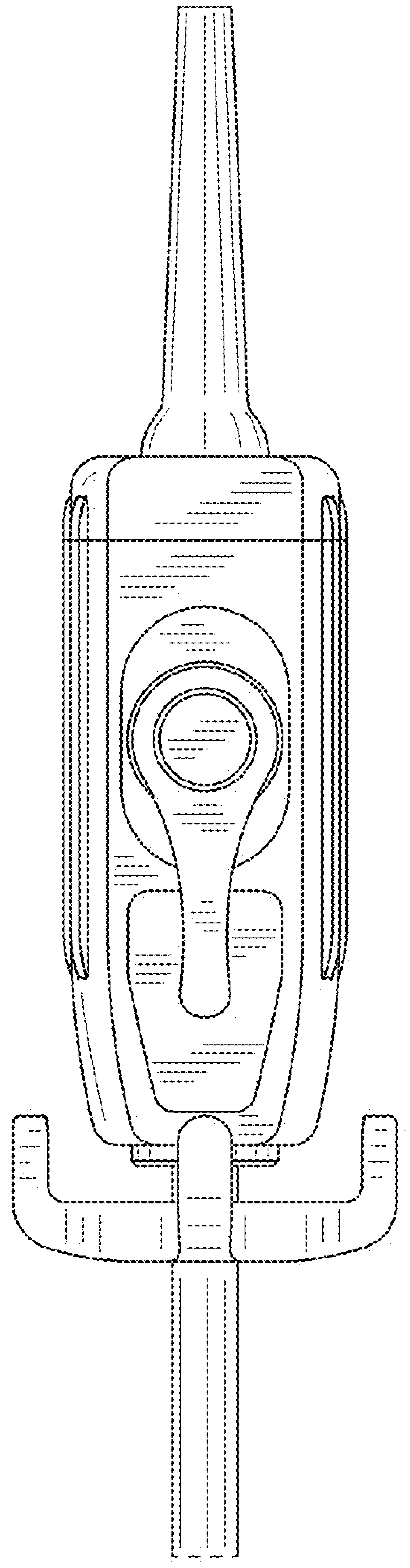


Fig. 14

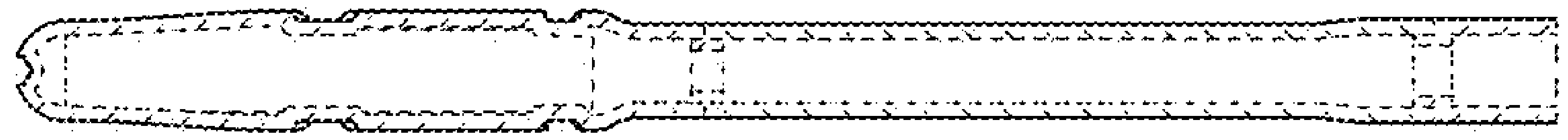


Fig.15

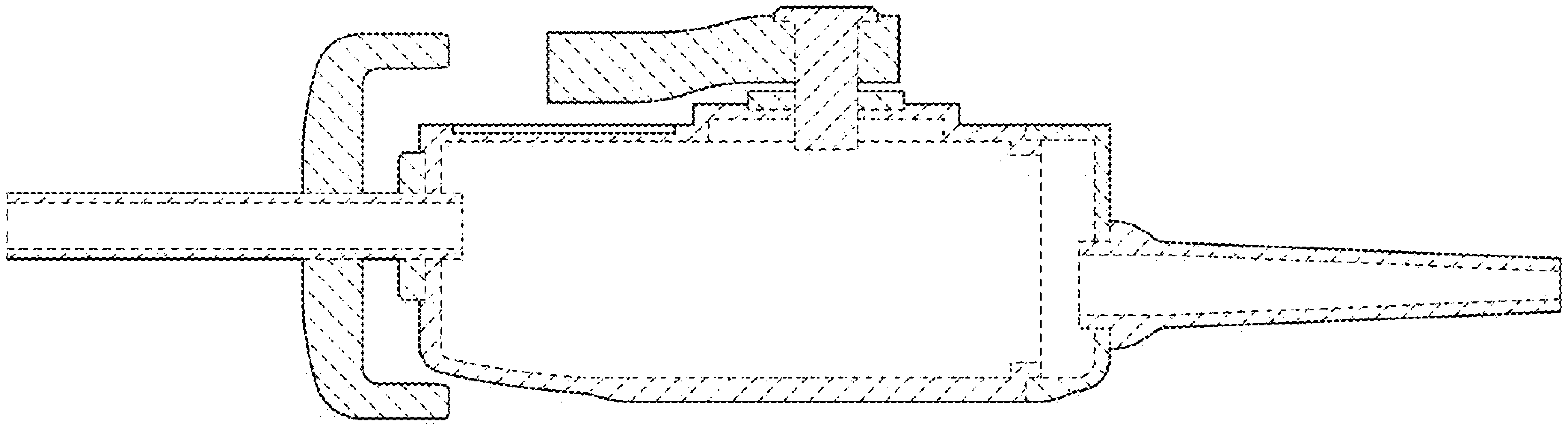


Fig.16

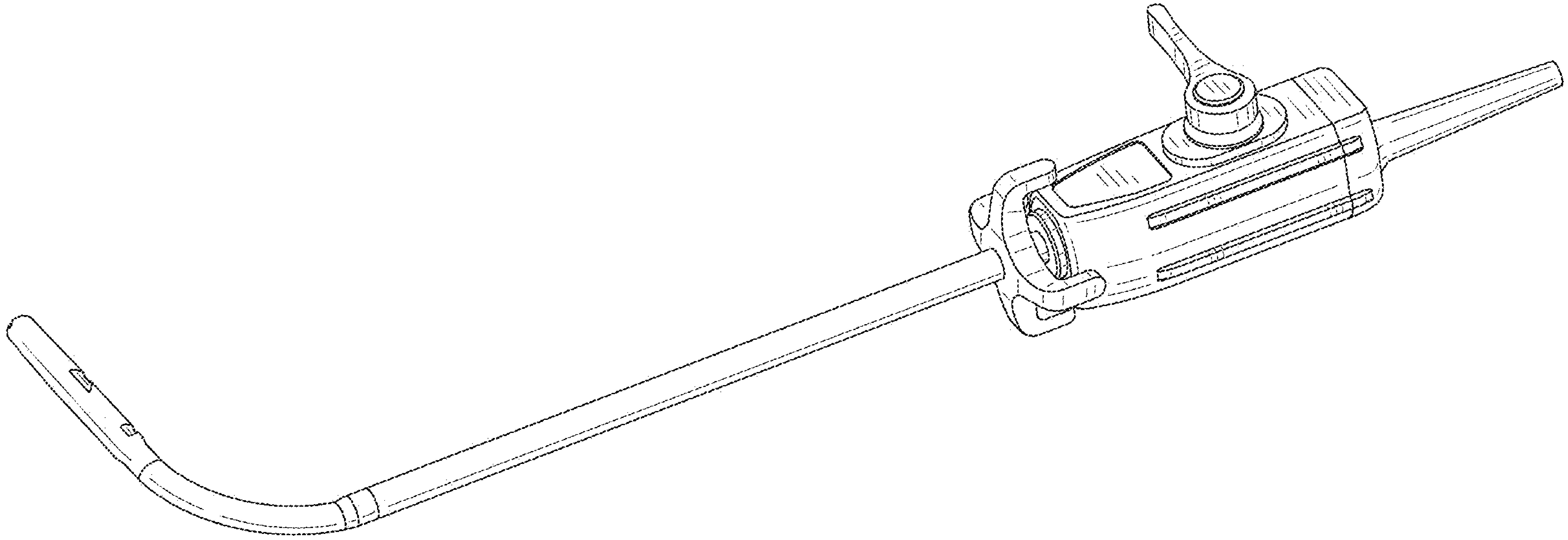


Fig. 17